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| Notice of References Cited | Application/Control No. 10/799,768 | Applicant(s)/Patent Under Reexamination INOUE ET AL. | |
| | Examiner Leslie J. Evanisko | Art Unit 2854 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-----------------|----------------|
| | A | US-6,599,613 | 07-2003 | Kasahara et al. | 428/140 |
| | B | US-6,573,877 | 06-2003 | Wedel et al. | 345/4 |
| | C | US-5,601,928 | 02-1997 | Katayama et al. | 428/500 |
| | D | US- | | | |
| | E | US- | | | |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------------------|----------------|
| | N | WO 01/45957 | 06-2001 | PCT | Fukushima et al. | --- |
| | O | WO 98/36420 | 08-1998 | PCT | Wedel et al. | --- |
| | P | JP 2004-34642 A | 02-2004 | Japan | --- | --- |
| | Q | JP 2000-111660 | 04-2000 | Japan | Osawa, Seiichi | --- |
| | R | JP 11-326548 | 11-1998 | Japan | --- | --- |
| | S | JP 2002-127389 | 05-2002 | Japan | --- | --- |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.